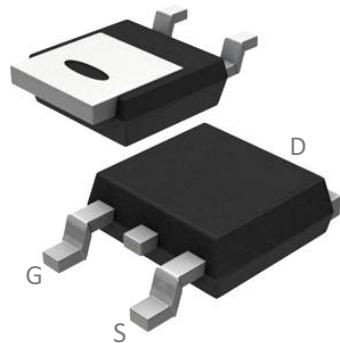


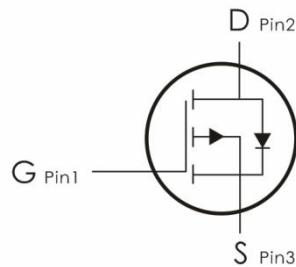
Description:

This P-Channel MOSFET uses advanced trench technology and design to provide excellent $R_{DS(on)}$ with low gate charge. It can be used in a wide variety of applications.



Features:

- 1) $V_{DS}=-100V, I_D=-20A, R_{DS(ON)}<100m\Omega$ @ $V_{GS}=-10V$ (Typ: $80m\Omega$)
- 2) Low gate charge.
- 3) Green device available.
- 4) Advanced high cell density trench technology for ultra low $R_{DS(ON)}$.
- 5) Excellent package for good heat dissipation.
- 6) MSL3



Package Marking and Ordering Information:

Part NO.	Marking	Package	Packing
DOD20P10	20P10	TO- 252	2500 pcs/Reel

Absolute Maximum Ratings: ($T_C=25^\circ C$ unless otherwise noted)

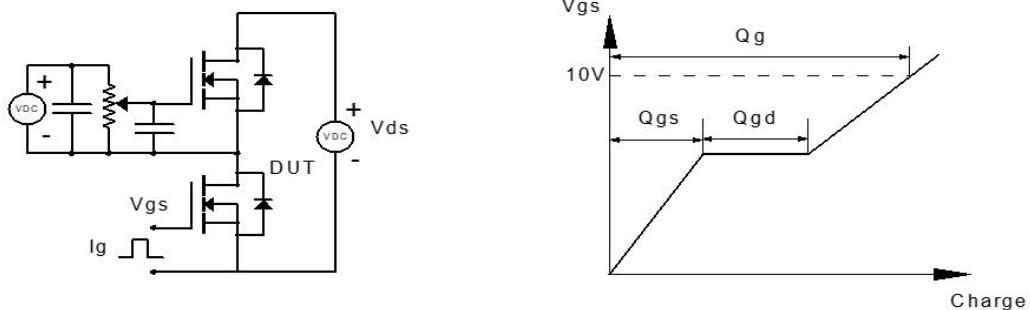
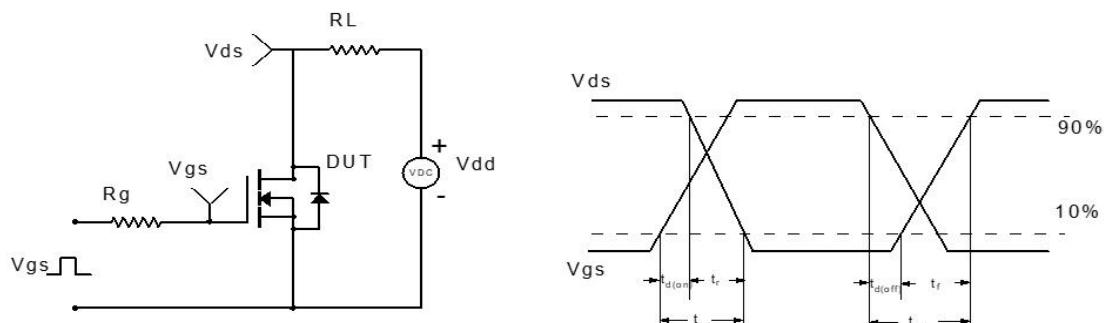
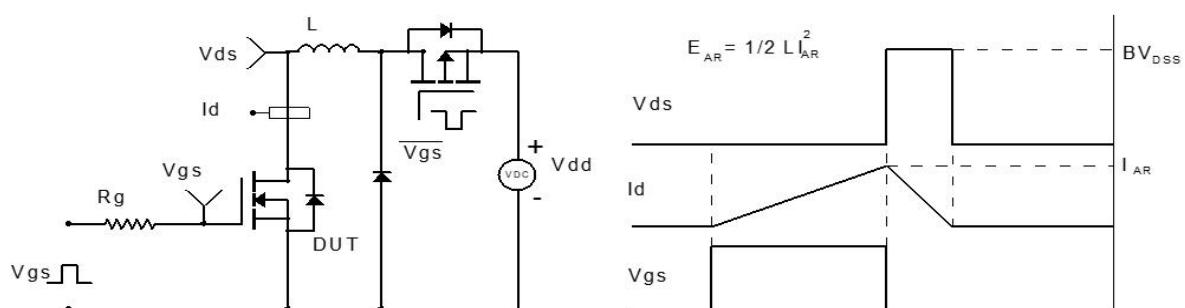
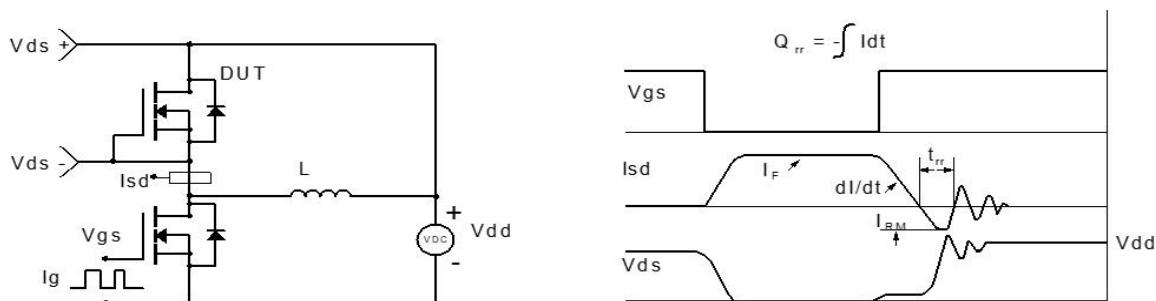
Symbol	Parameter	Ratings	Units
V_{DS}	Drain-Source Voltage	-100	V
V_{GS}	Gate-Source Voltage	± 20	V
I_D	Continuous Drain Current	-20	A
	Continuous Drain Current- $T_C=100^\circ C$	-14	
I_{DM}	Pulsed Drain Current ¹	-80	
P_D	Power Dissipation	66	W
E_{AS}	Single pulse avalanche energy ²	72	mJ
T_J, T_{STG}	Operating and Storage Junction Temperature Range	-55-+150	°C

Thermal Characteristics:

Symbol	Parameter	Max	Units
$R_{\theta JC}$	Thermal Resistance,Junction to Case	1.9	°C/W

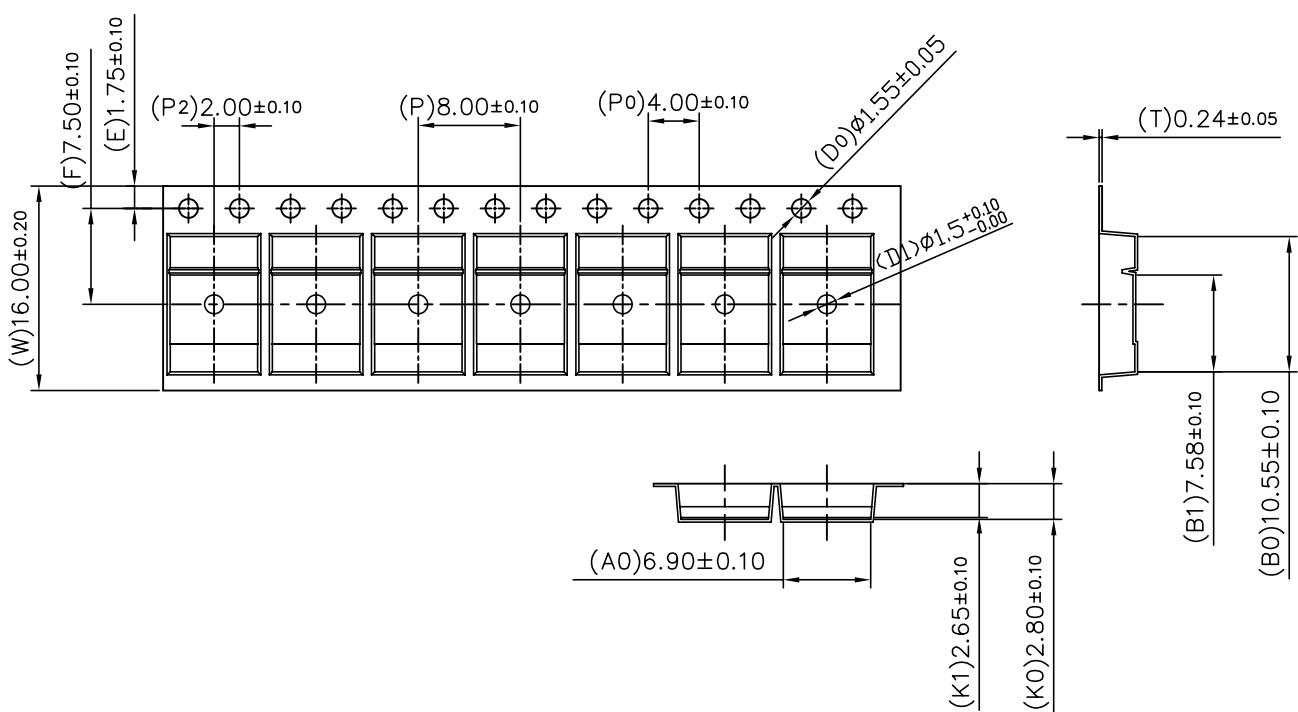
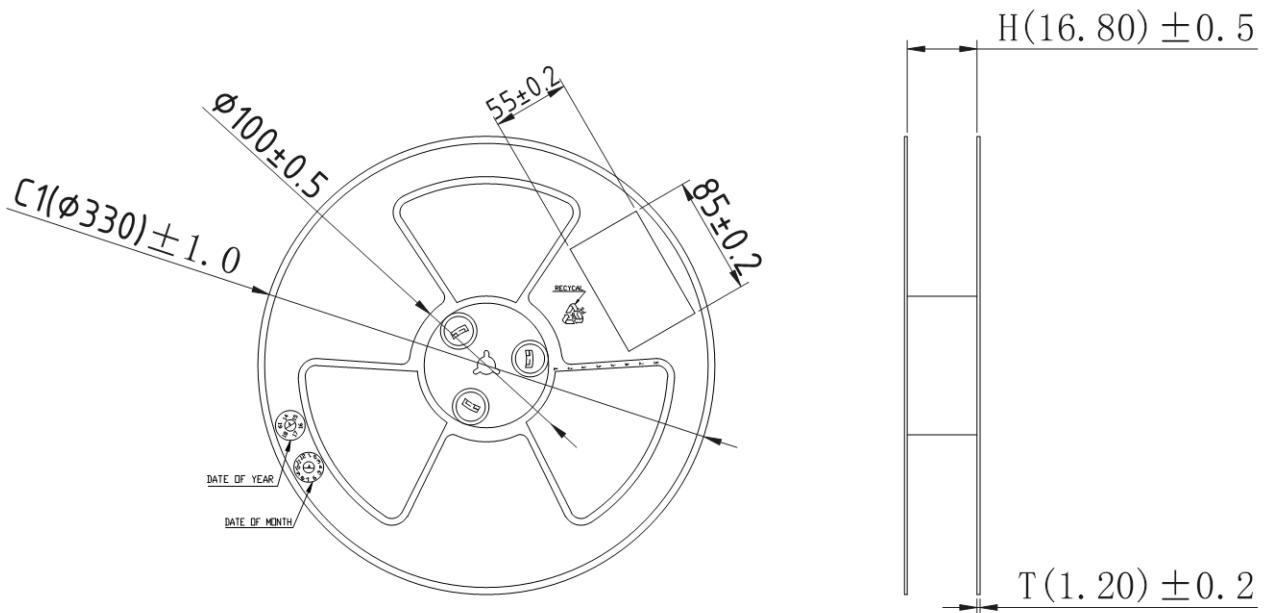
**Notes:**

1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature
2. EAS condition : $T_J=25^\circ\text{C}$, $V_{DD}=-50\text{V}$, $V_G=10\text{V}$, $L=0.5\text{mH}$
3. Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 0.5\%$

Test Circuit**Figure 1: Gate Charge Test Circuit & Waveform****Figure 2: Resistive Switching Test Circuit & Waveform****Figure 3: Unclamped Inductive Switching Test Circuit & Waveform****Figure 4: Diode Recovery Test Circuit & Waveform**

Tape & Reel Information

Dimensions in mm



Pulling direction →

Marking Information:

①. Doingter LOGO

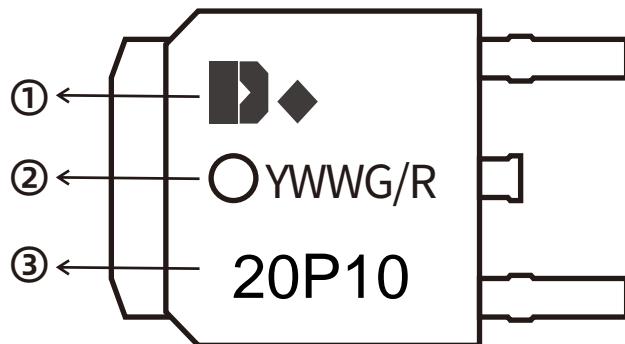
②. Date Code(YWWG / R)

Y : Year Code , last digit of the year

WW : Week Code(01-53)

G/R : G(Green) /R(Lead Free)

③. Part NO.



Previous Version

Version	Date	Subjects (major changes since last revision)
1.0	2024-09-11	Release of final version

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